Form PTO 144	9	U.S. DEPARTMENT		ATTY DOCKET NO. 250051US2S DIV		SERIAL NO. 10/796,180 New Application			
(Modified)		PATENT AND TRA	DEMARK OFFICE						
				APPLICANT					
LIST O	F REFE	RENCES CITED BY AF	PPLICANT	Mitsuhiro NOGUCHI, et al.					
				FILING DATE		GROUP			
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				U.S. PATENT DOCUMENTS					
EXAMINER INITIAL	2	DOCUMENT NUMBER	DATE	NAME CLASS		SUB FILING DATE CLASS IF APPROPRIATE			
Bu	AA	5,452,249	09/19/95	MIYAMOTO ET AL.					
	AB	6,563,746	05-2003	FUJIOKA ET AL.					
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	AD	6,091,640	07-2000	KAWAHARA ET AL.					
M	AE	5,835,436	11-1998	OOISHI					
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m	AO	2000-76872	03/14/00	JAPAN			Х		
Bu	AP	7-182886	07/21/95	JAPAN			· x		
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		OTHER RE	FERENCES (I	ncluding Author, Title, Date, Pertinen	t Pages, et	c.)			
Bn	AW	Jue-Hsien CHERN, et al., "Multilevel Metal Capacitance Models for CAD Design Synthesis Systems", IEEE ELECTRON DEVICE LETTERS, VOL. 13, NO. 1 January 1992, pgs: 32-34							
	AX				-				
	AY								
	AZ			Additional References sheet(s) attached					
Examiner Tuan T. Namen					Date Considered 8/9/04				
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		DOCUMENT NUMBER	DATE	COUNTRY	Y		TRANSLATION YES NO			
Pon	AO	2000-0023177	04/25/2000	KOREA (with corr. JP 2000-276887)			X			
1	AP	2000-276887	10/06/2000	JAPAN (with English Abstract)		-	×			
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Examiner Tuan T. Nguyen Date Considered 8/9/04  *Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.										
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